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San Francisco, California

Abstract Deadline: November 1, 1993

SYMPOSIA

A: AMORPHOUS SILICON TECHNOLOGY - 1994

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B: ADVANCED METALLIZATION FOR DEVICES AND CIRCUITS - SCIENCE, TECHNOLOGY, AND MANUFACTURABILITY - III

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F: EPITAXIAL OXIDE THIN FILMS AND HETEROSTRUCTURES

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G: RAPID THERMAL AND INTEGRATED PROCESSING III

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H: POLYCRYSTALLINE THIN FILMS - STRUCTURE, TEXTURE, PROPERTIES AND APPLICATIONS

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K: LIQUID CRYSTAL POLYMERS

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L: ELECTROLUMINESCENT POLYMERS

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N: BETTER CERAMICS THROUGH CHEMISTRY VI

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Q: MATERIALS IN MUSICAL INSTRUMENTS

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S: HIGH-TEMPERATURE SUPERCONDUCTORS - MULTILAYERS, INTERFACES, AND APPLICATIONS

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W: THEORY AND SIMULATION OF TIME-DEPENDENT PROCESSES IN MATERIALS

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